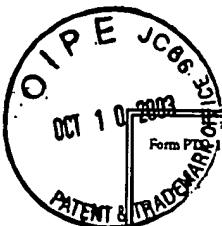


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI40-356		SERIAL NO. 10/626,876	
<i>6-28-05</i> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT: Micron Technology, Inc.			
		FILING DATE July 24, 2003		GROUP 2635				
U.S. PATENT DOCUMENTS								
*Examiner's Initials		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
<i>ED</i>	AA	4,843,354	06/1989	Fuller et al.		333	81	
	AB	5,448,770	09/1995	Hietala et al.		455	126	
	AC	5,696,025	12/1997	Violette et al.		437	175	
	AD	5,741,462	04/1998	Nova et al.		422	68.1	
	AE	3,694,776	09/1972	Linder		333	17	
	AF	3,921,094	11/1975	Schaible		331	1	
	AG	5,121,407	06/1992	Partyka et al.		375	1	
	AH	5,334,951	08/1994	Hogeboom		331	1	
<i>ED</i>	AI	5,705,947	01/1998	Jeong		327	270	
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country		Class	Subclass	Translation
	AJ							Yes
	AK							No
	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AM							
	AN							
	AO							
EXAMINER <i>ED</i>		DATE CONSIDERED <i>6-23-05</i>						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					ATTY. DOCKET NO. MI40-356	SERIAL NO. 10/626,876	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT James E. O'Toole et al.		
					FILING DATE July 24, 2003	GROUP Unassigned	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>EQ</i>	AA	4,897,662 ✓	01/30/90	Lee et al.	343	701	
	AB	4,942,393 ✓	07/17/90	Warkaa et al.	340	825.72	
	AC	5,235,326 ✓	08/10/93	Beigel et al.	340	825.54	
	AD	5,317,309 ✓	05/31/94	Vercellotti et al.	340	825.54	
	AE	5,519,386	05/21/96	Toberge	340	825.54	
	AF	5,649,295 ✓	07/15/97	Shober et al.	455	38.2	
	AG	6,249,212 B1	06/19/01	Beigel et al.	340	10.34	
	AH	5,491,718 ✓	02/13/96	Gould et al.	375	205	
<i>EAS</i>	AI	5,606,322 ✓	02/25/97	Allen et al.	343	173	
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
<i>EQZ</i>	AL	2 238 210 A	05/1991	Great Britain			Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>Edwin C. O'Toole</i>				DATE CONSIDERED <i>6-23-05</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449 <i>7-24-03</i> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					ATTY. DOCKET NO. MI40-356	SERIAL NO. 09/151,359	
					APPLICANT James E. O'Tool, et al.		
					FILING DATE Filed Herewith	GROUP 2635	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>EDC</i>	AA	3,299,424	01/17/1967	VINDING	343	6.5	
	AB	3,852,755	12/03/1974	WORKS, ET AL.	343	701	
	AC	3,924,320	12/09/1975	ALTMAN, ET AL.	29	578	
	AD	4,075,632	02/21/1978	BALDWIN, ET AL.	343	6.8	
	AE	4,190,383	02/26/1980	KEMP	343	18	
	AF	4,384,288	05/17/1983	WALTON	340	825.34	
	AG	4,514,731	04/30/1985	FALCK, ET AL.	340	825.08	
	AH	4,478,881	10/23/1984	BARTUR	427	90	
	AI	4,572,976	02/25/1986	FOCKENS	307	524	
	AJ	4,656,463	04/07/1987	ANDERS, ET AL.	340	572	
	AK	4,700,179	10/13/1987	FANCHER	340	572	
<i>EDC</i>	AL	4,724,427	02/09/1988	CARROLL	340	572	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
<i>EDC</i>	AM	0 172 445 A1	07/95	EPO			
	AN	0 682 382 A2	04/95	EPO			
	AO	0 682 382 A3	05/95	EPO			
	AP	DE 3212876 A1	04/83	GERMANY			
<i>EDC</i>	AQ	0 616 429 A1	01/94	EPO			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
<i>EDC</i>	AR		"Micron Morning Report", The Idaho Statesman, July 16, 1993				
<i>EDC</i>	AS.		"A Low-Power Spread Spectrum CMOS RFIC for Radio Identification Applications", by John R. Tuttie, RF Expo West, pp. 216-222, March 22-24, 1994, San Jose, CA.				
<i>EDC</i>	AT		Provisional Application, Serial No. 60/023,321, Filed July 30, 1996.				
EXAMINER	<i>Eden Carroll</i>			DATE CONSIDERED	<i>6-22-05</i>		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1440 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. M140-356		SERIAL NO. 09/151,359	
				APPLICANT James E. O'Toole, et al.			
				FILING DATE Filed Herewith		GROUP 2635	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>EA</i>	AA	4,743,864	05/10/1988	NAKAGAWA, ET AL.	331	1 A	
	AB	4,746,830	05/24/1988	HOLLAND	310	313	
	AC	4,783,646	11/08/1988	MATSUZAKI	340	572	
	AD	4,786,903	11/22/1988	GRINDAHL, ET AL.	340	825.540	
	AE	4,800,543	01/24/1989	LYNDON-JAMES ET AL.	368	10	
	AF	4,816,839	03/28/1989	LANDT	343	795	
	AG	4,827,395	05/02/1989	ANDERS, ET AL.	364	138	
	AH	4,853,705	08/01/1989	LANDT	343	803	
	AI	4,854,328	08/08/1989	POLLACK	128	736	
	AJ	4,857,893	08/15/1989	CARROLL	340	572	
	AK	4,862,160	08/29/1989	EKCHIAN, ET AL.	340	825.54	
<i>EA</i>	AL	4,868,908	09/19/1989	PLÉSS, ET AL.	323	267	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM						Yes
	AN						No
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
<i>EA</i>	AR	Provisional Application, Serial No. 60/023,318, Filed July 30, 1996.					
<i>EA</i>	AS	"CMOS Analog Integrated Circuits Based on Weak Inversion Operation", by Eric Vittoz and Jean Fellrath, IEEE Journal of Solid State Circuits, Vol. SC-12, No. 3, June 1997.					
<i>EA</i>	AT	"Digital RF/ID Enhances GPS", by John R. Tuttle, Proceedings of the Second Annual Wireless Symposium, pp. 406-411 February 15-18, 1994, Santa Clara, CA					
EXAMINER	<i>Edna C. O'Toole</i>			DATE CONSIDERED <i>6-23-05</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. MI4D-356	SERIAL NO. 09/151,359		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT James E. O'Toole, et al.			
				FILING DATE Filed herewith	GROUP 2635		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>EJ</i>	AA	4,870,419	09/26/1989	BALDWIN	342	50	
	AB	4,888,591	12/19/1989	LANDT, ET AL.	342	44	
	AC	4,890,072	12/26/1989	ESPE, ET AL.	331	11	
	AD	4,912,471	03/27/1990	TYBURSKI, ET AL.	342	42	
	AE	4,926,182	05/15/1990	OHTA, ET AL.	342	44	
	AF	4,952,889	08/28/1990	IRWIN, ET AL.	332	128	
	AG	5,030,807	07/09/1991	LANDT, ET AL.	235	375	
	AH	5,072,194	12/10/1991	CHIEVALLIER	330	260	
	AJ	5,075,691	12/24/1991	GARAY, ET AL.	343	830	
	AJ	5,081,458	01/14/1992	MEUNIER	342	44	
	AK	5,086,389	02/04/1992	HASSETT, ET AL.	364	401	
<i>EJ</i>	AL	5,103,156	04/07/1992	JONES, ET AL.	320	35	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM						Yes
	AN						No
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
<i>EJ</i>	AR		Mitsubishi Motors Corporation Web Page, 1995.				
<i>EJ</i>	AS		"Micron RFID Communications Protocol Manual", July 22, 1993 Pre-Release Version 0.95, pp. 1-71.				
<i>EJ</i>	AT		Waugh, Raymond, "Designing Detectors for RF/ID Tags"; RF Expo West Conference, January 29-February 1, 1995; pp. 1-12.				
EXAMINER	<i>Eden Choller</i>		DATE CONSIDERED	6-23-05			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. MI40-356	SERIAL NO. 09/151,359			
				APPLICANT James E. O'Toole, et al.				
				FILING DATE Filed Herewith	GROUP 2635			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>EJ</i>	AA	5,122,687	06/16/1992	SCHMIDT	307	471		
	AB	5,128,938	07/07/1992	BORRAS	370	95.1		
	AC	5,130,668	07/14/1992	EMSLIE, ET AL.	330	281		
	AD	5,134,085	07/28/1992	GILGEN, ET AL.	437	52		
	AE	5,142,292	08/25/1992	CHANG	343	742		
	AF	5,143,820	09/01/1992	KOTECHA	430	314		
	AG	5,144,314	09/01/1992	MALMBERG, ET AL.	342	44		
	AH	5,151,624	09/29/1992	STEGHERR, ET AL.	307	498		
	AI	5,153,583	10/06/1992	MURDOCH	340	825.54		
	AJ	5,164,985	11/17/1992	NYSEN, ET AL.	380	9		
	AK	5,175,774	12/29/1992	TRAUX, ET AL.	382	8		
<i>EJ</i>	AL	5,191,295	03/02/1993	NECOECHEA	328	155		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AU							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
<i>EJ</i>	AR	Analysis and Design of Analog Integrated Circuits, Paul R. Gray & Robert G. Meyer, pages 657-681, 1993.						
<i>EJ</i>	AS	Analog Integrated Circuits for Communication (Principles, Simulation and Design), Donald O. Pederson & Kartikaya Mayaram, pages 431-433 1991.						
<i>EJ</i>	AT	A Precise Four-Quadrant Multiplier With Subnanosecond Response, Barrie Gilbert, IEEE Journal of Solid State Circuits, pages 365-373, 1968.						
EXAMINER	<i>Ed C. Reeder</i>			DATE CONSIDERED	<i>6-23-05</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. MI40-356	SERIAL NO. 09/151,359			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT James E. O'Toole, et al.				
				FILING DATE Filed Herewith	GROUP 2635			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>ED</i>	AA	5,206,609	04/27/1993	MJUSKOVIC	331	57		
	AB	5,218,343	06/08/1993	STOBBE, ET AL.	340	572		
	AC	5,231,273	07/27/1993	CASWELL, ET AL.	235	385		
	AD	5,252,979	10/12/1993	NYSEN	342	50		
	AE	5,272,367	12/21/1993	DENNISON, ET AL.	257	306		
	AF	5,281,927	01/25/1994	PARKER	331	1 A		
	AG	5,287,112	02/15/1994	SCHUERMANN	342	42		
	AH	5,294,928	03/15/1994	COOPER	341	142		
	AI	5,300,875	04/05/1994	TUTTLE	320	20		
	AJ	5,300,896	04/05/1994	SUSSELMAN	330	260		
	AK	5,311,186	05/10/1994	UTSU, ET AL.	342	51		
<i>ED</i>	AL	5,323,150	06/21/1994	TUTTLE	340	825,540		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	
		AM					No	
		AN						
		AO						
		AP						
		AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
<i>ED</i>	AR	Muller & Kamins, "Device Electronics for Integrated Circuits", 1977, John & Wiley & Sons, 2 nd Edition, pages 157-160.						
<i>ED</i>	AS	Fink & Christiansen, "Electronic Engineer's Handbook", 1989, McGraw-Hill Book Company, 3 rd Edition, pages 7-41 to 7-42, 8-38 to 8-39, and 9-66 to 9-69.						
<i>ED</i>	AT	E.C. Young, "Dictionary of Electronics", 1979, pgs. 7 & 124.						
EXAMINER	<i>Ed - CD Bell</i>		DATE CONSIDERED <i>6-23-05</i>					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1440 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					ATTY. DOCKET NO. MI40-356	SERIAL NO. 09/151,359	
					APPLICANT James E. O'Toole, et al.		
					FILING DATE Filed Herewith		
					GROUP 2635		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>EPA</i>	AA	5,340,968	08/23/1994	WANTABE, ET AL.	235	380	
	AB	5,355,513	10/11/1994	CLARKE, ET AL.	455	20	
	AC	5,361,403	11/01/1994	DENT	455	74	
	AD	5,365,192	11/15/1994	WAGNER	330	252	
	AE	5,365,351	11/15/1994	SNODGRASS, ET AL.	375	1	
	AF	5,374,930	12/20/1994	SCHUERMANN	342	42	
	AG	5,394,159	02/28/1995	SCHNEIDER	343	700	
	AH	5,394,444	02/28/1995	SILVEY, ET AL.	375	374	
	AI	5,406,263	04/11/1995	TUTTLE	340	572	
	AJ	5,406,297	04/11/1995	CASWELL, ET AL.	343	741	
	AK	5,412,351	03/02/1995	NYSTROM, ET AL.	332	103	
<i>EPA</i>	AL	5,412,665	03/02/1995	GRUODIS, ET AL.	371	27	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
<i>EPA</i>	AR	N.J. Woods, et al. "One micrometre scale self-aligned cobalt disilicide Schottky barrier diodes", Electronics Letters, Vol. 31, No. 21, pages 1878-1880 Oct. 1995.					
<i>EPA</i>	AS	Shenai Krishna "Characteristics of LPVD WS ₂ /N-Si Schottky Contacts", IEEE Electron Device Letters, Vol. 12, No. 4, 1 April 1991, pgs. 169-171.					
<i>EPA</i>	AT	Wolf, "Silicon Processing for the VLSI Era, Volume 3 2; Process Integration, 1990, Lattice Press, pp. 65 and 195.					
EXAMINER	<i>Ed O'Toole</i>			DATE CONSIDERED	<i>6-23-05</i>		
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT James E. O'Toole, et al.			
				FILING DATE Filed Herewith	GROUP 2635		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>EJF</i>	AA	5,416,434	05/16/1995	KOOTSTRA, ET AL.	327	113	
	AB	5,420,737	05/30/1995	EBERHARDT, ET AL.	361	813	
	AC	5,423,074	06/06/1995	DENT	455	74	
	AD	5,430,441	07/04/1995	BICKLEY, ET AL.	340	825.54	
	AE	5,444,223	08/22/1995	BLAMA	235	435	
	AF	5,446,761	08/29/1995	NAG, ET AL.	375	317	
	AG	5,446,765	08/29/1995	LEGER	375	359	
	AI	5,448,110	09/05/1995	TUTTLE	257	723	
	AJ	5,448,242	09/05/1995	SHARPE, ET AL.	342	42	
	AJ	5,448,772	09/05/1995	GRANDFIELD	455	333	
	AK	5,450,087	09/12/1995	HURTA, ET AL.	342	42	
<i>EJF</i>	AL	5,461,385	10/24/1995	ARMSTRONG	342	42	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AM						No
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
<i>SJL</i>	AR	Buechler, J., "Silicon-Millimeter-Wave Circuits for Receivers & Transmitters" IEEE Microwave & Millimeter-Wave Monolithic etc.					
		Symp. Pp 67-70 (1988).					
	AS						
	AT						
EXAMINER	<i>Ed Cullen</i>		DATE CONSIDERED	<i>G-23-05</i>			
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. MI40-356	SERIAL NO. 09/151,359			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT James E. O'Toole, et al.				
				FILING DATE Filed Herewith	GROUP 2635			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>EDR</i>	AA	5,471,212	11/28/1995	SHARPE, ET AL.	342	51		
	AB	5,478,991	12/26/1995	WANTABE, ET AL.	235	375		
	AC	5,485,520	01/16/1996	CHAUM, ET AL.	380	24		
	AD	5,489,546	02/06/1996	AHMAD, ET AL.	437	57		
	AE	5,499,214	03/12/1996	MORI, ET AL.	365	222		
	AF	5,500,650	03/19/1996	SNODGRASS, ET AL.	342	42		
	AG	5,511,090	04/03/1996	DENTON	375	205		
	AH	5,525,992	06/11/1996	FROSCHERMEIER	342	42		
	AI	5,541,583	07/30/1996	MANDELBAUM	340	825,540		
	AJ	5,541,585	07/30/1996	DUHAME, ET AL.	340	825,690		
	AK	5,568,512	10/22/1996	ROTZELL	375	221		
<i>EDR</i>	AL	5,576,647	11/19/1996	SUTARDJA, ET AL.	327	108		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER	<i>Edw CR Reen</i>			DATE CONSIDERED	<i>6-23-05</i>			
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT James E. O'Toole, et al.				
				FILING DATE Filed Herewith		GROUP 2635		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>Ed C</i>	AA	5,606,323	02/25/1997	HEINRICH, ET AL.	342	51		
	AB	5,621,412	04/15/1997	SHARPE, ET AL.	342	51		
	AC	5,623,224	04/22/1997	YAMADA, ET AL.	327	333		
	AD	5,640,151	<i>✓</i>	REIS				
	AE	5,649,296	07/15/1997	MacLELLAN, ET AL.	455	38.2		
	AF	5,657,359	08/12/1997	SAKAE, ET AL.	375	376		
	AG	5,668,560	09/16/1997	EVANS, ET AL.	343	702		
	AH	5,677,667	10/14/1997	LESESKY, ET AL.	340	431		
	AI	5,686,864	11/11/1997	MARTIN, ET AL.	331	1 A		
	AJ	5,686,920	11/11/1997	HURTA, ET AL.	342	42		
	AK	5,703,509	12/30/1997	HIRATA	327	119		
<i>Ed C</i>	AL	5,719,550	02/17/1998	BLOCH, ET AL.	340	426		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
	AM						Yes	No
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER	<i>Ed C Spell</i>			DATE CONSIDERED	<i>6-23-05</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. MI40-356	SERIAL. NO. 09/151,359			
				APPLICANT James E. O'Toole, et al.				
				FILING DATE Filed Herewith	GROUP 2635			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>ED</i>	AA	5,721,678	02/24/1998	WIDL	364	424.04		
	AB	5,721,783	02/24/1998	ANDERSON	381	68.6		
	AC	5,726,630	03/10/1998	MARSH, ET AL.	340	572		
	AD	5,774,022	06/30/1998	GRIFFIN, ET AL.	331	1 A		
	AE	5,780,916	07/14/1998	BERGER, ET AL.	257	471		
	AF	5,815,042	09/29/1998	CHOW, ET AL.	331	57		
	AO	5,901,349	05/04/1999	GUEGNAUD, ET AL.	455	302		
	AH	5,907,789	05/25/1999	KOMATSU	438	649		
	AI	5,940,006	08/17/1999	MacLELLAN	340	825.54		
	AJ	5,970,398	10/19/1999	TUTTLE	455	193.1		
	AK	6,122,494	09/19/2000	TUTTLE	455	193.1		
<i>ED</i>	AL	6,130,602	—	O'TOOLE	—	—		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER	<i>Eden C. Delle</i>			DATE CONSIDERED	<i>6-23-05</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								